

## ABSTRACT OF THE DISCLOSURE

The semiconductor integrated circuit device includes an internal power supply circuit placed between a prescribed one of a plurality of internal circuits and a power supply interconnection for converting a level of an external power supply potential to supply an internal power supply potential to the prescribed internal circuit, and a control circuit for conducting a self-test of the semiconductor integrated circuit device. The control circuit detects a current amount being supplied from the internal power supply circuit to the prescribed internal circuit. The detected result is externally output via a data input/output unit.